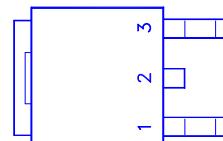
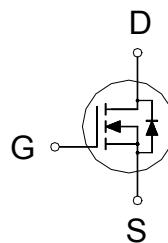


**NIKO-SEM**
**N-Channel Logic Level Enhancement  
Mode Field Effect Transistor**
**P3055LDG**  
TO-252 (DPAK)  
Halogen-Free & Lead-Free
**PRODUCT SUMMARY**

$V_{(BR)DSS}$	$R_{DS(ON)}$	$I_D$
25	50mΩ	12A

**ABSOLUTE MAXIMUM RATINGS ( $T_c = 25^\circ\text{C}$  Unless Otherwise Noted)**

PARAMETERS/TEST CONDITIONS		SYMBOL	LIMITS	UNITS
Gate-Source Voltage		$V_{GS}$	$\pm 20$	V
Continuous Drain Current	$T_c = 25^\circ\text{C}$	$I_D$	12	A
	$T_c = 100^\circ\text{C}$		8	
Pulsed Drain Current <sup>1</sup>		$I_{DM}$	45	
Avalanche Energy	$L = 0.1\text{mH}$	$E_{AS}$	60	mJ
Power Dissipation	$T_c = 25^\circ\text{C}$	$P_D$	48	W
	$T_c = 100^\circ\text{C}$		20	
Operating Junction & Storage Temperature Range		$T_j, T_{stg}$	-55 to 150	°C
Lead Temperature ( $1/16''$ from case for 10 sec.)		$T_L$	275	

**THERMAL RESISTANCE RATINGS**

THERMAL RESISTANCE	SYMBOL	TYPICAL	MAXIMUM	UNITS
Junction-to-Case	$R_{\theta JC}$		3	
Junction-to-Ambient	$R_{\theta JA}$		75	°C / W
Case-to-Heatsink	$R_{\theta CS}$	1		

<sup>1</sup>Pulse width limited by maximum junction temperature.
**ELECTRICAL CHARACTERISTICS ( $T_c = 25^\circ\text{C}$ , Unless Otherwise Noted)**

PARAMETER	SYMBOL	TEST CONDITIONS	LIMITS			UNIT
			MIN	TYP	MAX	
<b>STATIC</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0\text{V}, I_D = 250\mu\text{A}$	25			V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	0.8	1.2	2.5	
Gate-Body Leakage	$I_{GSS}$	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			$\pm 250$	nA
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 20\text{V}, V_{GS} = 0\text{V}$			25	
		$V_{DS} = 20\text{V}, V_{GS} = 0\text{V}, T_J = 125^\circ\text{C}$			250	μA
On-State Drain Current <sup>1</sup>	$I_{D(ON)}$	$V_{DS} = 10\text{V}, V_{GS} = 10\text{V}$	12			A

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Drain-Source On-State Resistance <sup>1</sup>	$R_{DS(ON)}$	$V_{GS} = 5V, I_D = 12A$		70	120	$m\Omega$
		$V_{GS} = 10V, I_D = 12A$		50	90	
Forward Transconductance <sup>1</sup>	$g_{fs}$	$V_{DS} = 15V, I_D = 12A$		16		S
<b>DYNAMIC</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = 15V, f = 1MHz$		450		$pF$
Output Capacitance	$C_{oss}$			200		
Reverse Transfer Capacitance	$C_{rss}$			60		
Total Gate Charge <sup>2</sup>	$Q_g$			15		$nC$
Gate-Source Charge <sup>2</sup>	$Q_{gs}$			2.0		
Gate-Drain Charge <sup>2</sup>	$Q_{gd}$			7.0		
Turn-On Delay Time <sup>2</sup>	$t_{d(on)}$			6.0		$nS$
Rise Time <sup>2</sup>	$t_r$			6.0		
Turn-Off Delay Time <sup>2</sup>	$t_{d(off)}$			20		
Fall Time <sup>2</sup>	$t_f$			5.0		
<b>SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS (<math>T_c = 25^\circ C</math>)</b>						
Continuous Current	$I_S$				12	$A$
Forward Voltage <sup>1</sup>	$V_{SD}$	$I_F = I_S, V_{GS} = 0V$			1.5	
Reverse Recovery Time	$t_{rr}$	$V_{DS} = 15V, R_L = 1\Omega$		30		$nS$
Reverse Recovery Charge	$Q_{rr}$			0.043		$\mu C$

<sup>1</sup>Pulse test : Pulse Width  $\leq 300 \mu sec$ , Duty Cycle  $\leq 2\%$ .<sup>2</sup>Independent of operating temperature.**REMARK: THE PRODUCT MARKED WITH “P3055LDG”, DATE CODE or LOT #**

**NIKO-SEM**

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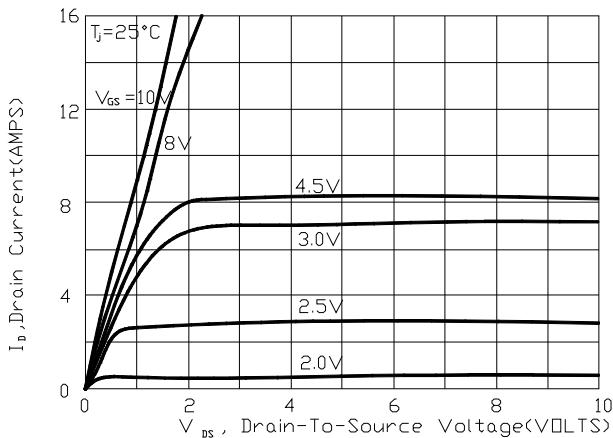


Fig.1 On-Resistance Variation with Temperature

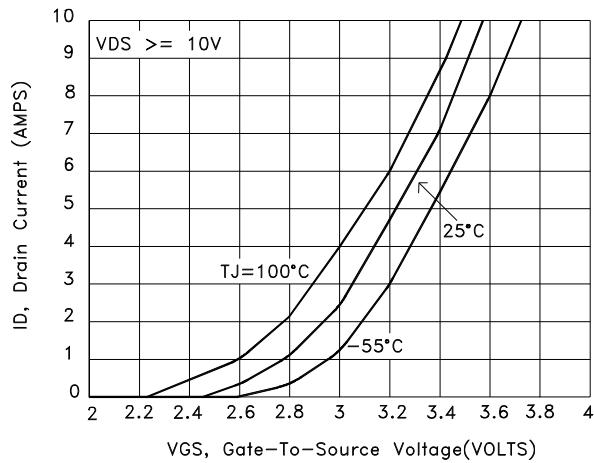


Fig.2 Transfer Characteristics

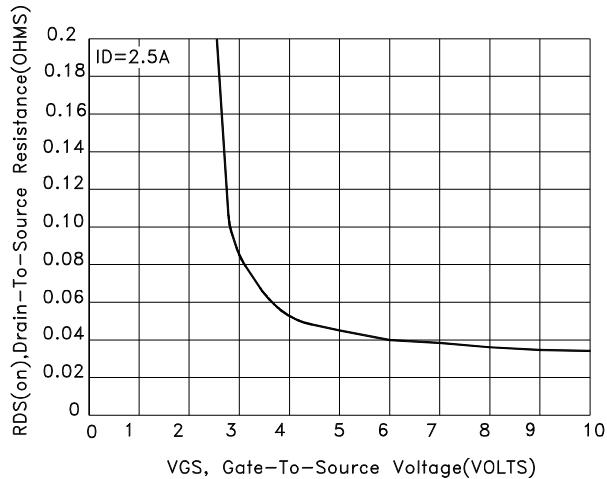


Fig.3 On-Resistance versus Gate-to-Source Voltage

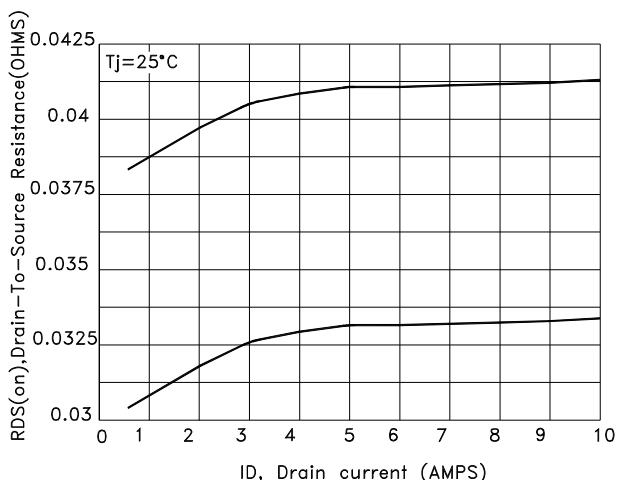


Fig.4 On-Resistance versus Drain Current and Gate Voltage

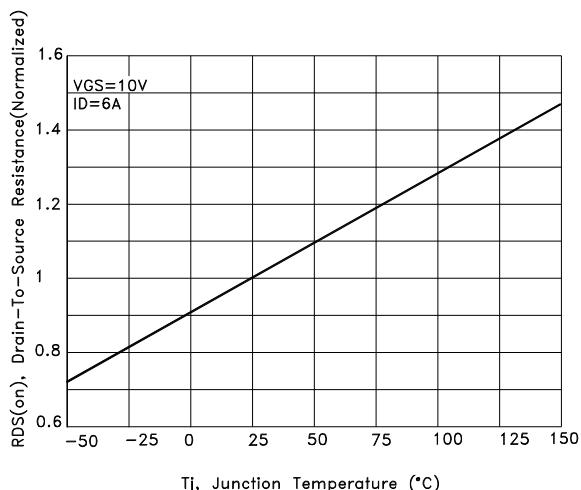


Fig.5 On-Resistance Variation with Temperature

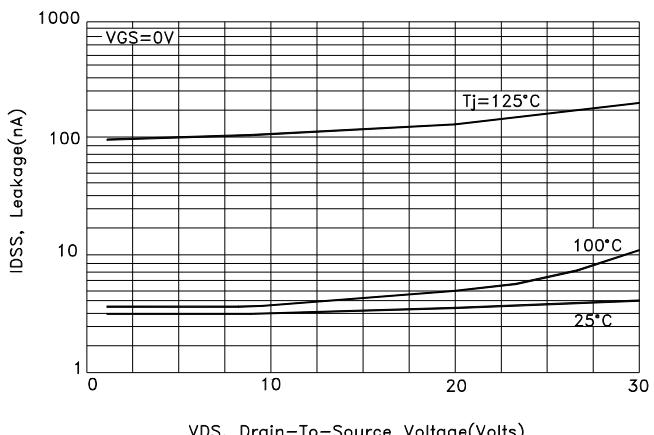


Fig.6 Drain-to-Source Leakage Current versus Voltage

## TO-252 (DPAK) MECHANICAL DATA

Dimension	mm			Dimension	mm		
	Min.	Typ.	Max.		Min.	Typ.	Max.
A	8.9	9.5	10.4	H	0.8	1.27	2.03
B	2.19	2.3	2.435	I	6.35	6.6	6.8
C	0.35	0.5	0.65	J	4.8	5.34	5.5
D	0.89		1.5	K	0.5		1.5
E	0.35		0.65	L	0.4	0.76	0.89
F	0.0		0.23	M	3.96		5.18
G	5.4		6.2	N			

